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Application/Control No.	

Applicant(s)/Patent under Reexamination

09/892,622 Examiner MIYAWAKI ET AL.

Cong-Lac Huynh

2178

	SEARCHED			
Class	Subclass	Date	Examiner	
715	500	7/27/2007	CLH	
	501.1	7/27/2007	CLH	
	530	7/27/2007	CLH	
	531	7/27/2007	CLH	
	764	7/27/2007	CLH	
	769	7/27/2007	CLH	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NO (INCLUDING SEARC)
	DATE	EXMR
East	7/27/2007	CLH
IEEE	7/27/2007	CLH
Google	7/27/2007	CLH
8		